

OLED Sample For Electron Microscope Examination And Method For Making The Same

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Abstract

An OLED sample for electron microscope examination sequentially includes a substrate, a first electrode, an organic layer , a second electrode, and a protecting layer. By providing electron beams to strike the OLED
10 sample and by controlling the thickness of the OLED sample within 0.2 μm to 0.3 μm , the opportunity that molecules of the organic layer can be stroked by the electron beam can be increased so as to obtain a clear image of the OLED sample.